## Measurement and production – one challenge!

2013 International Congress of Metrology – 7 to 10 October – Paris (France)

"Portable measurement, embedded measurement, extremely accurate or just fit for purpose, which to take at what point?

Measurement plays an essential role in any quality system, recognizing its importance in decision making: Managing risks, indicating performance, meeting specifications and better quality control.

All that will be discussed during this event! "

Bernard Larquier – BEA Métrologie Chairman of the Congress



The International Metrology Congress is the place for a broad technical exchange - unique in Europe – **assembling all major players in the world of measurement**: industrial users, technical experts, associations, academics, manufacturers and service providers.

It showcases and exemplifies the added value of measurement: as a tool for process improvement and risk management.

As part of the programme, six **industrial roundtables** will explore the following topics:

- Medical biology: mastering your analysis
- Measurement and traceability in food processing
- Measurement fuelling low carbon technologies
- The metrological requirements specific to high-tech fields
- Metrology challenges for nanotechnologies
- Risk management and product conformity

Nearly 180 lectures will explore a variety of subjects, covering:

- Major technical areas such as mechanics, temperature, form and surface, force and pressure, power ...
- **New challenges:** measurements in biological and medical sectors, environment and challenges in energy, nanotechnologies,...

## Other news for the 2013 edition:

- an introduction to career's in measurement and metrology,
- Recent progress of many European research programmes and their industrial applications.

**Technical visits** to LNE, CEA and PSA Peugeot Citroën are planned are planned to further complement the conference talks and discussions.

The Congress is organised by the Collège Français de Metrologie in partnership with BIPM, OIML, Euramet, the NCSLi, NPL and METAS for international level. This is heavily supported by industrials on the organizing committee such as EDF, Novartis, PSA Peugeot Citroën, Hexagon Metrology, Trescal, Acac, BEA Métrologie, CETIAT, IMQ, and INSA.

Since 2012, the 2013 Congress is sponsored by two leading industrial partners: Apave - A + Metrology specialist for risk control, test and measurement, and Carl Zeiss, international expert in precision optical solutions.

Hexagon Metrology and Implex also play an important part in the development of the event.

As in previous years, the Congress will take advantage of its co-location with the major measurement trade show for measurement, Mesurexpovision (part of enova Paris). During lunches at noon and cocktails in the evenings, all participants and exhibitors can be mingle in the **Metrology Village**, a unique opportunity to build a real relationship and technical exchanges that go beyond a simple "business" touch.

By booking the exhibition space as part of this Village, exhibitors can also benefit from advantageous pricing conditions and access to conferences rooms and lunches of the Congress.

**Exhibitors registered to the Village Metrology early April are**: Aerométrologie, Apave - A + Metrology, AOIP, Aremeca, Carl Zeiss, CETIAT, Czech Metrology Institute, Delta Mu, Dimelco, Graduate School of Engineering, Elcowa, Eotech, EPI Labels , Eurotek, Felix informatique, Geomnia, Guildline Instruments, Hexagon Metrology, Implex, Insavalor, JRI Maxant, ESA Lot - Quantum Design, Lycée Jules Richard, MB Electronics, MEATEST, Mettler Toledo, Nikon Metrology, PCB Piezotronics, Radwag Balances & Scales , Sematec, Sika France, Symetrie, Tegam, Testo Industrial Services, Wika Instruments.

The full programme and registration is now available online with secure payment at www.metrologie2013.com. Registration is now open for one, two days or the entire event.

## Information:

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